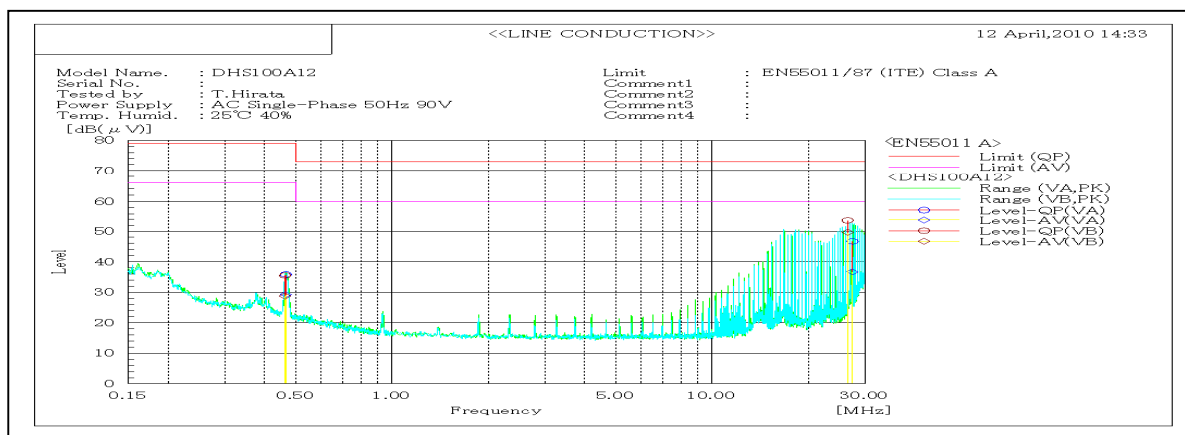
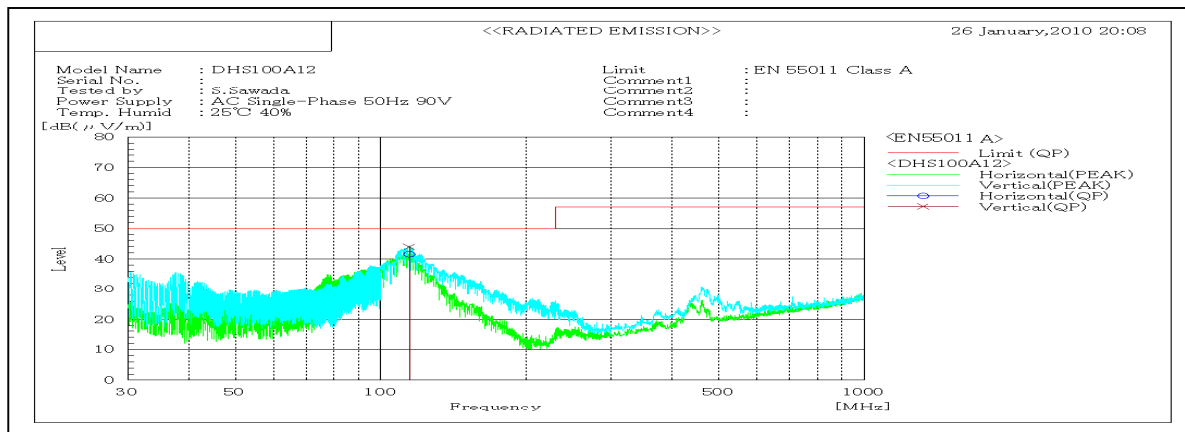


DATA SHEET		Date	26-Apr-10
Model	DHS100A12	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Hirata



Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.46365		VB	25.5	18.8	10	35.5	28.8	79	66	43.5	37.2	Pass	
0.46592		VA	25.7	19.1	10.1	35.8	29.2	79	66	43.2	36.8	Pass	
26.5276		VB	42.6	38.6	11	53.6	49.6	73	60	19.4	10.4	Pass	
27.467		VA	36	25.9	10.7	46.7	36.6	73	60	26.3	23.4	Pass	



Frequency MHz	Harm	Polariz ation	Level Check	Stabili ty	Reading dB(μV)			Space Loss dB	Level dB(mW)			Limit dB(mW)	Limit dB(mW)	Limit dB(mW)	Margin dB			Pass/ Fail	Height cm	Angle deg	Remark
					QP	AV	PK		QP	AV	PK				QP	AV	PK				
114.53		H		Stable	61.3			-19.7	41.6			50			8.4			Pass	158	331	
114.506		V		Stable	63.7			-19.7	44			50			6			Pass	158	236	

## DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

### 1. Line conduction



### 2. Radiated emission

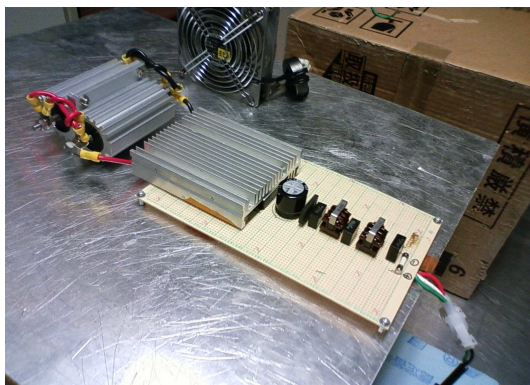


Test: EMI

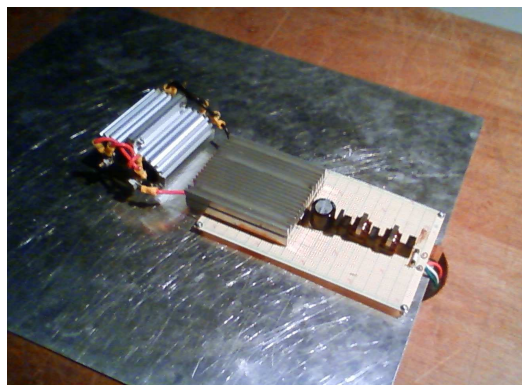
Model Name:DHS50A/DHS100A Series

## ○ Photographs of Test Set-Up

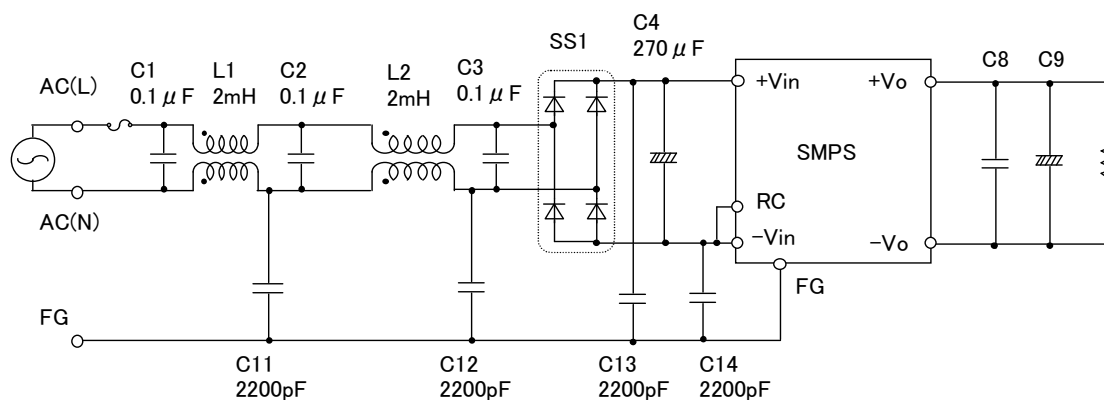
### LINE CONDUCTION



### RADIATED EMISSION



## ○ Test circuit



L1,L2	:	SC-05-200(NEC TOKIN)
SS1	:	D3SBA60(SINDENGEN)
C8	:	DHS50A24/DHS100A24 4.7 μ F
		Others 10 μ F
C9	:	DHS50A05/DHS100A05 2200 μ F
		DHS50A12/DHS100A12 470 μ F
		DHS50A15/DHS100A15 470 μ F
		DHS50A24/DHS100A24 220 μ F